



Specification for Approval

Date: 2016/08/19

深圳臺慶 Customer:

	TAI-TECH P/N:	PAS4420F-352K-F	10
	CUSTOMER P/N:		
	DESCRIPTION:		
	QUANTITY:	pcs	<u>; </u>
REM	IARK:		
	Cus	stomer Approval Feedba	ck

西 北 臺 慶 科 技 股 份 有 限 公 司 TAI-TECH Advanced Electronics Co., Ltd

■ 西北臺慶科技股份有限公司

TAI-TECH Advanced Electronics Co., Ltd Headquarter:

NO.1 YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI,

TAO-YUAN HSIEN, TAIWAN, R.O.C. TEL: +886-3-4641148 FAX: +886-3-4643565

http://www.tai-tech.com.tw

E-mail: sales@tai-tech.com.tw

□ 東莞臺慶精密電子有限公司

DONGGUAN TAI-TECH ADVANCED ELECTRONICS CO., LTD JITIGANG MANAGEMENT DISTRICT, HUANGJIANG, DONGGUAN, **GUANGDONG, CHINA**

TEL: +86-769-3365488 FAX: +86-769-3366896

E-mail: twnwe@pub.dgnet.gd.cn

Office:

金亨國際有限公司

KAMHENG INTERNATIONAL LIMITED TEL: +86-852-25772033 FAX: +86-852-28817778

□ 臺慶精密電子(昆山)有限公司

TAI-TECH ADVANCED ELECTRONICS(KUNSHAN) CO., LTD SHINWHA ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA

TEL: +86-512-57619396 FAX: +86-512-57619688

E-mail: hui@tai-tech.com.tw

Office:

北欣國際有限公司

NORTH STAR INTERNATIONAL LIMITED TEL: +86-512-57619396 FAX: +86-512-57619688

Sales Dep.

APPROVED	CHECKED
管哲頎	曾詩涵
Eric Kuan	Angela Tseng

R&D Center

APPROVED	CHECKED	DRAWN
楊祥忠	徐鋒強	孔妍暄
Mike Yang	Gemini Hsu	Chloe Kung

Telecoil-antennas Inductors

PAS4420F-352K-F10

	ECN HISTORY LIST								
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN				
1.0	16/01/27	新 發 行	楊祥忠	徐鋒強	孔妍暄				
/-++-			1						
備									
註									

Telecoil-antennas Inductor

PAS4420F-352K-F10

1.Features

- 1. Hearing Aid Compatibility-/Telecoil-antennas;
- 2. PAS4420F-series realizes small size and low profile. 4.4x2.0x2.0 mm.
- 3. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
- 4. Meets the T3 FCC requirements(HAC-Act) acc. ANSI C63.19

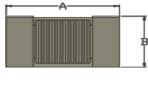
(Halogen) Halogen-free

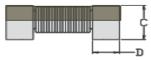


2. Applications

- 1. T-coil/HAC-coil for hearing and aid compatible cell phones .
- 2. Decoupling in RF and IF-circuit .
- 3. Transponder antenna.

3. Dimensions

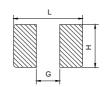




Size	A(mm)	B(mm)	C(mm)	D(mm)
PAS4420F	4.55±0.25	2.2±0.25	2.0±0.2	0.98 ref.

Units: mm

Recommend PC Board Pattern



L(mm)	G(mm)	H(mm)
4.6	2.5	2

4. Part Numbering



A: Series

B: Dimension Lx H

C: Lead Free Code

 $\begin{array}{lll} \text{D: Inductance} & 352 = 3500 \text{ uH} \\ \text{E: Inductance Tolerance} & \text{K} = \pm 10\% \\ \text{F: Test Frequency} & 10 \text{ KHz} \\ \end{array}$

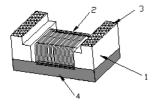
5. Specification

Part Number	Inductance (uH) ±10%	fL0 (kHz)	SRF MHz(min)	RDC (Ω) max	Rated current (mA) max.
PAS4420F-352K-F10	3500	10	1	85	20

Note:

- 1. Test frequency : Inductor(L) : 10KHz /0.1V;

6. Material List



NO	Items	Materials
1	Core	Ferrite
2	Wire	Copper Wire
3	Terminal	Tin (Pb free)
4	Adhesive	UV or Epoxy

7. Reliability and Test Condition

Item	Performance	Test Condition		
Operating temperature	-40~+125℃ (Including self - temperature rise)			
Storage temperature	-40~+125°C (on board)			
Electrical Performance Tes	st			
Inductance		HP4284A,CH11025,CH3302,CH1320,CH1320S		
inductance	Refer to standard electrical characteristics list.	LCR Meter.		
DCR		CH16502,Agilent33420A Micro-Ohm Meter.		
Saturation Current (leat)	∆L≤20% typical.	Saturation DC Current (Isat) will cause L0		
Saturation Current (Isat)	△L≥20% typical.	to drop \triangle L(%)(keep quickly).		
		Heat Rated Current (Irms) will cause the coil temperature rise		
Heat Rated Current (Irms)	Approximately △T≤40°C	$\triangleT({}^{\circ}\!$		
neat Rated Current (IIIIIs)	Approximately \(\times 1 \) \(\times 40 \) \(\times 1 \)	1.Applied the allowed DC current(keep 1 min.).		
		2.Temperature measured by digital surface thermometer		

Reliability Test		
		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles)
		Temperature : 125±2°C
Life Test		Applied current : rated current
		Duration: 1000±12hrs
		Measured at room temperature after placing for 24±2 hrs
		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles
Load Humidity		Humidity: 85±2%R.H,
		Temperature : 85°C ±2°C
		Duration: 1000hrs Min. with 100% rated current
		Measured at room temperature after placing for 24±2 hrs
		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles 1. Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and
Moisture Resistance	Appearance : No damage. Inductance : within±10% of initial value	keep 3 hours, cool down to 25°C in 2.5hrs.
		3. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and
	Q : Shall not exceed the specification value.	keep 3 hours, cool down to 25°C in 2.5hrs,keep at 25°C for 2 hrs then keep at -10°C for 3 hrs
	RDC: within ±15% of initial value and shall not	4. Keep at 25°C 80-100%RH for 15min and vibrate at the
	exceed the specification value	frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.
Thermal		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle
shock		Step1 : -40±2℃ 30±5min
		Step2 : 25±2°C ≤0.5min
		Step3 : 125±2°C 30±5min
		Number of cycles: 500
	-	Measured at room temperature after placing for 24±2 hrs
Vibration		Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes
Vibration		Equipment: Vibration checker Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3
		Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations).

Item	Performance	Test Condition								
				Peak value	Normal			Velocity		
Shock			Type	(g's)	duration (D) (ms)		Wave form	change (Vi)ft/sec		
	Appearance : No damage.	-	SMD	50	11		Half-sine	11.3		
	Inductance: within±10% of initial value	L	Lead	50	11		Half-sine	11.3		
Bending	Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value			Shall be mounted on a FR4 substrate of the following dimensions: >=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth: >=0805:1.2mm <0805:0.8mm duration of 10 sec.						
Soderability	More than 95% of the terminal electrode should be covered with solder。	Preheat: 150℃,60sec.。 Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5℃。 Flux for lead free: Rosin. 9.5%。 Dip time: 4±1sec。 Depth: completely cover the termination								
	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Number of heat cycles: 1								
Resistance to Soldering		Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate								
Heat			260 ±5(temp)	(solder 1	0 ±1	25mn	m/s ±6 mm	/s		
Terminal Strength		tim Re Wi tes (>I tes ap gra	nes.(IP eflow Pr ith the c sted, ap 0805:1h sted. Th oplied fo adually	rofiles component oply a force kg , <=080 his force sh	mounted of the state of the sta	ODClasson a Foother the	PCB with the side of a side force sh	ellow for 2 to be device being tall be applied		
			\/ s	DUT		pres	ss tool	wide		

8. Soldering and Mounting

8-1. Attention regarding P.C.B. bending

The following shall be considered when designing P.C.B.'S

(1)P.C.B. shall be designed so that products are not subjected to the mechanical stress for board warpage.

(Good example)



Products shall be located in the sideways direction (Length :a<b) to against the mechanical stress.

(2) Products location on P.C.B.

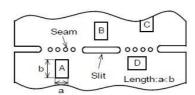
(Poor example)

Products (A,B,C,D) shall be located carefully

to prevent mechanical stress when warping the board.

Products may be subjected to the mechanical

stress in the order of A>C>B = D.



8-2. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

8-2.1 Solder re-flow:

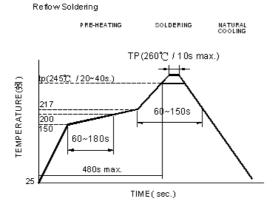
Recommended temperature profiles for re-flow soldering in Figure 1.

8-2.2 Soldering Iron(Figure 2):

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150°C
- Never contact the ceramic with the iron tip
- · Use a 20 watt soldering iron with tip diameter of 1.0mm

- 355 $^{\circ}$ C tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5 sec.



Reflow times: 3 times max.

Fig.1

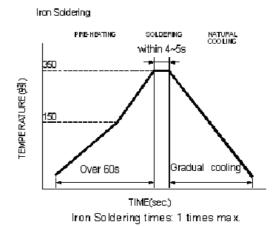
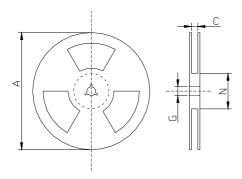


Fig.2

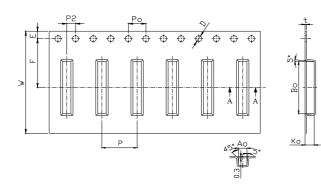
9. Packaging Information

9-1. Reel Dimension



Туре	A(mm)	C(mm)	G(mm)	N(mm)
7"x12mm	180±2	16.5±1	13.5±0.5	100±2

9-2. Tape Dimension / 12mm

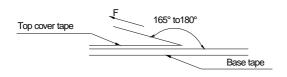


9-3. Packaging Quantity

Chip size	4420		
Reel	1000		
Reel Size	7"x12mm		

Series	Size	P(mm)	Po(mm)	P2(mm)	Bo(mm)	Ao(mm)	Ko(mm)	t(mm)
PAS	4420	8.0±0.1	4.0±0.1	2.0±0.1	5.00±0.10	2.5±0.10	2.1±0.10	0.3±0.05
Series	Size	D(mm)	E(mm)	F(mm)	W(mm)			
PAS	4420	1.5+0.1/-0	1.75±0.1	5.5±0.1	12±0.30			

9-4. Tearing Off Force



The force for tearing off cover tape is 10 to 80 grams in the arrow direction under the following conditions(referenced ANSI/EIA-481-C-2003 of 4.11 standard).

Room Temp.	Room Humidity	Room atm	Tearing Speed	
(℃)	(%)	(hPa)	mm/min	
5~35	45~85	860~1060	300	

Application Notice

- Storage Conditions (component level)
- To maintain the solderability of terminal electrodes:
- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
 - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
 - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



號碼(No.): CE/2015/92842

日期(Date): 2015/09/15

頁數(Page): 1 of 4

Test Report

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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(耀鑚科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUCIAN CITY, JIANGSU)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

WIREWOUND SERIES(FILM BACKING)

樣品型號(Style/Item No.)

TWI · SWF · SWC_F · PAS · WCM-L2NF · WCM-F2SNF SERIES

收件日期(Sample Receiving Date)

2015/09/11

測試期間(Testing Period)

2015/09/11 TO 2015/09/15

測試結果(Test Results)

請見下一頁 (Please refer to next pages).

Troy Chang[®] Manage Signed for and on loghalf of SGS TAIWAN LTD: Chemical Laboratory - Taipei

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號碼(No.): CE/2015/92842

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頁數(Page): 2 of 4

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測試結果(Test Results)

測試部位(PART NAME)No.1

: 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result) No.1
銻 / Antimony (Sb)		參考US EPA 3052方法,以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n. d.

備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量。(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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Test Report

號碼(No.): CE/2015/92842

日期(Date): 2015/09/15

頁數(Page): 3 of 4

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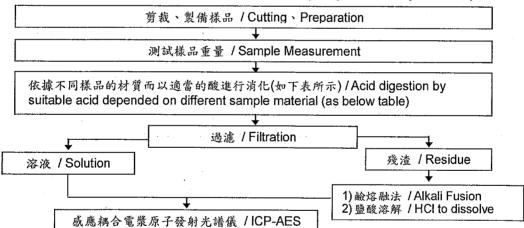
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- 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 測試人員:楊登偉 / Name of the person who made measurement. Climbgreat Yang
- 測試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang

元素以 ICP-AES 分析的消化流程圖 (Flow Chart of digestion for the elements analysis performed by ICP-AES)



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 /
	Aqua regia, HNO ₃ , HCI, HF, H ₂ O ₂
玻璃 / Glass	硝酸,氫氟酸 / HNO ₃ /HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO ₃
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H ₂ SO ₄ , H ₂ O ₂ , HNO ₃ , HCI
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

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桃園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.

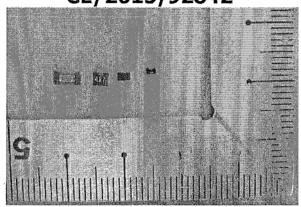
(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中堰區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

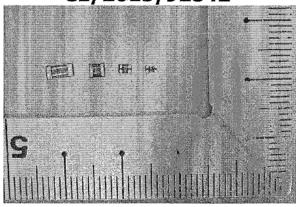
(江蘇省宿還市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

> * 照片中如有箭頭標示,則表示為實際檢測之樣品/部位。* (The tested sample / part is marked by an arrow if it's shown on the photo.)

> > CE/2015/92842



CE/2015/92842



** 報告結尾 (End of Report) **

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